2013
Optics + Photonics
25–29 August 2013

Technical Program
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NanoScience + Engineering
Solar Energy + Technology
Organic Photonics + Electronics
Optical Engineering + Applications

Conferences & Courses
25–29 August 2013

Exhibition
27–29 August 2013

Location
San Diego Convention Center
San Diego, California, USA
Polarization Science and Remote Sensing VI

Conference 8873 · Room: Conv. Ctr. 32B
Monday–Thursday 26–29 August 2013 · Proceedings of SPIE Vol. 8873

Monday 26 August

Posts-Monday
Room: Conv. Ctr. Exhibition Hall B2  ·  Mon 5:30 to 7:30 pm
Conference attendees are invited to attend the poster session on Monday evening. Come view the posters, enjoy light refreshments, ask questions, and network with colleagues in your field. Authors of poster papers will be present to answer questions concerning their papers. Attendees are required to wear their conference registration badges to the poster sessions. Poster authors: view poster presentation guidelines at http://spie.org/x00293.xml

Photooelastic modulator non-idealities in magneto-optical polarization measurements, Stefano Vandendriessche, Thierry Verbiest, Katholieke Univ. Leuven (Belgium)  ·  [8873-37]
Polarization characteristics of dust aerosol particles, Zengzhou Hao, Delu Pan, Fang Gong, Haiqing Huang, The Second Institute of Oceanography, SOA (China)  ·  [8873-38]
Optical characterization of amber from Chiapas, Mexico, Guadalupe Lopez, Rafael Espinoza-Luna, Ctr. de Investigaciones en Optica, A.C. (Mexico); Claudio Frausto-Reyes, Ctr. de Investigaciones en Optica A.D. (Mexico)  ·  [8873-39]
A compact and robust method for spectropolarimetry, William B. Sparks, Space Telescope Science Institute (United States)  ·  [8873-40]
Oriental tomography of optical axes directions distributions of multilayer biological tissues birefringent polycrystalline networks, Natalia I. Zabolotna, Rostyslav Y. Dovhaliuk, Vinnytsya National Technical Univ. (Ukraine)  ·  [8873-41]
A portable imaging Mueller matrix polarimeter based on a hybrid modulation approach, Israel J. Vaughn, J. Scott Tyo, College of Optical Sciences, The Univ. of Arizona (United States)  ·  [8873-42]
Analyzing vector diversification, Andrey Alulin, J. Scott Tyo, College of Optical Sciences, The Univ. of Arizona (United States)  ·  [8873-43]
CALIOP receiver transient response study, Xiaomei Lu, Yongxiang Hu, Yunhua Cao, Haiying Li, Xidian Univ. (China)  ·  [8873-44]

9:30 am: Real-time combined reflection and transmission ellipsometry for film-substrate systems, M. Elhazly-Zaghloil, Cairo Univ. (Egypt)  ·  [8873-4]
9:20 am: Evaluation of calibration methods for visible-spectrum division-of-focal-plane polarimeters, Samuel B. Powell, Washington Univ. in St. Louis (United States)  ·  [8873-5]

Session 2
Room: Conv. Ctr. 32B  ·  Wed 9:40 am to 11:10 am
Mathematics of Coherence, Polarization, and Scattering

Polarization

Session Chair: Joseph A. Shaw, Montana State Univ. (United States)
9:40 am: Mathematical tools for the analysis and exploitation of polarimetric measurements (Invited Paper), Jose J. Gil Perez, Univ. de Zaragoza (Spain)  ·  [8873-6]
10:30 am: Partial Mueller matrix polarimeter design, Andrei Alulin, J. Scott Tyo, College of Optical Sciences, The Univ. of Arizona (United States)  ·  [8873-7]
10:30 am: Partial Mueller matrix polarimeter design, Andrei Alulin, J. Scott Tyo, College of Optical Sciences, The Univ. of Arizona (United States)  ·  [8873-7]

Wednesday 28 August

Session 1
Room: Conv. Ctr. 32B  ·  Wed 8:00 am to 9:10 am
Polarization Metrology and Instrumentation

Session Chair: Julia M. Craven-Jones, Sandia National Labs. (United States)
8:00 am: Infrared wire grid polarizers: metrology and modeling, Matthew C. George, Jonathon Bergquist, Rymunya Petrova, Bin Wang, Eric W. Gardner, MOXTEK, Inc. (United States)  ·  [8873-1]
8:20 am: Assessing consistency of a Mueller matrix measurement by rotation of the sample under test, Thomas A. Germer, National Institute of Standards and Technology (United States)  ·  [8873-2]
8:40 am: Single-angle-of-incidence single-element rotating-polarizer (Single SERP) ellipsometer for film-substrate systems, A. R. M. Zaghloil, Cairo Univ. (Egypt)  ·  [8873-3]

11:40 am: Influence of polarization phenomenology on material discriminability using multi-view polarimetric imagery, Chabitha Devanar, South Dakota State Univ. (United States); Michael Gartley, John R. Schott, Rochester Institute of Technology (United States)  ·  [8873-9]
12:00 pm: How clear-sky polarization varies with wavelength in the visible and near infrared, Nathan J. Pust, Joseph A. Shaw, Montana State Univ. (United States)  ·  [8873-10]
Lunch Break  ·  [8873-11]